DMD Implementation of a Single Pixel Camera Based on Compressed Sensing

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Pressure is on Digital Signal Processing

- Shannon/Nyquist sampling theorem
 - no information loss if we sample at 2x signal bandwidth
- DSP revolution: sample first and ask questions later



- Increasing *pressure* on DSP hardware, algorithms
 - ever faster sampling and processing rates
 - ever larger dynamic range
 - ever larger, higher-dimensional data
 - ever lower energy consumption
 - ever smaller form factors
 - multi-node, distributed, networked operation
 - radically new sensing modalities
 - communication over ever more difficult channels

Sensing by Sampling

- Long-established paradigm for digital data acquisition
 - sample data (A-to-D converter, digital camera, ...)
 - *compress* data (signal-dependent, nonlinear)
 - brick wall to performance of modern acquisition systems



Sparsity

 Many signals can be *sparsely represented* in some representation/basis (Fourier, wavelets, ...)







 $K \ll N$ large wavelet coefficients

N wideband signal samples





 $K \ll N$ large Gabor coefficients

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From Samples to Measurements

- Shannon/Nyquist sampling theorem
 - must sample at 2x signal bandwidth
 - too pessimistic for many signal classes
 - worst case bound for any bandlimited data
- Compressive sensing (CS) principle [Donoho; Candes, Romberg, Tao; Rice, ...]

"sparse signal statistics can be recovered from a small number of *non-adaptive linear measurements*

- integrates sensing, compression, processing
- enables sub-Nyquist "measuring"
- leverages new *sparse* data representations
- based on new *uncertainty principles* that extend Heisenberg's
- features *random* projections/measurements
- signal recovery via optimization (linear programming)





• Spikes and sines (Fourier) (Heisenberg)





$$\Phi = \mathrm{idct}(I)$$



• Spikes and "random basis"



$$\Psi = I$$

• Spikes and "random sequences" (codes)





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Compressive Sensing

- Measure linear projections onto *incoherent* basis where data is *not sparse*
 - random "white noise" is *universally incoherent*
 - mild "over-sampling" $M \approx O(K \log(N/K)) \ll N$



Reconstruct via nonlinear optimization (linear programming)

CS Hallmarks

- CS changes the rules of the data acquisition game
 - beats the Nyquist limit
 - exploits a priori signal *sparsity* information
 - slogans: "sample less, compute more"
- Universal
 - same random projections / hardware can be used for any compressible signal class (generic)
- Democratic
 - each measurement carries the same amount of information
 - simple encoding
 - robust to measurement loss and quantization
 - natural "dimensionality reduction" for posing vision tasks
- Asymmetrical (most processing at decoder)
- Random projections weakly encrypted

1 Chip DLP™ Projection





TI Digital Micromirror Device (DMD)





1080p



0.55SVGA



0.7XGA



SXGA+



HD2



576P



DLP 1080p --> 1920 x 1080 resolution



(Pseudo) Random Optical Projections

- Binary patterns are loaded into mirror array:
 - light reflected towards the lens/photodiode (1)
 - light reflected elsewhere (0)
 - pixel-wise products summed by lens



- Pseudorandom number generator outputs measurement basis vectors
- Mersenne Twister
 - Binary sequence (0/1)
 - Period 219937-1





[Matsumoto/Nishimura, 1997]



Single Sensor Camera



Potential for:

new modalities

beyond what can be sensed by CCD or CMOS imagers

- low cost
- low power









First Image Acquisition

ideal 4096 pixels



205 wavelets



409 wavelets



image at DMD array



820 random meas.



1638 random meas.



CS Video Imaging

- Incoherent projections in space-time (random)
- Reconstruct using 3-D wavelets (localized in space-time)



M. Wakin & R. Baraniuk

original 64x64x64



frame-by-frame 2-D CS recon 20000 coeffs, MSE = 18.4



M. Wakin & R. Baraniuk

3-D wavelet thresholding 2000 coeffs, MSE = 3.5



joint 3-D CS recon 20000 coeffs, MSE = 3.2



Color CS Camera



Color Imaging with CS Camera





Mandrill 32x32





Mandrill 64x64





Multispectral/Hyperspectral Imaging

Carousel of Differing Photodiodes



Dual Photodiode Sandwich







Broadband vs. Narrow-Region (Near-IR/UV)



ala the Foveon **Image Array**

UDT Sensors, Inc.





More Complex Photodetectors



http://micro.magnet.fsu.edu/primer/digitalimaging/concepts/photomultipliers.html

Multisensor DMD Camera



Conclusions

Compressive sensing

- exploit image sparsity information; beat Nyquist
- based on new uncertainty principles
- "sample smarter", "universal hardware"
- integrates sensing, compression, processing

Ongoing research

- new kinds of *imagers*: image and video
- *information scalability* for vision applications
 reconstruction > approximation > estimation > classification > detection
- multi-camera *light field* acquisition and processing (3-D)
- fast algorithms (DSP)
- *R/D* analysis of CS (quantization)
- new "analog-to-information" converters (analog CS)

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